

100147144-1002404

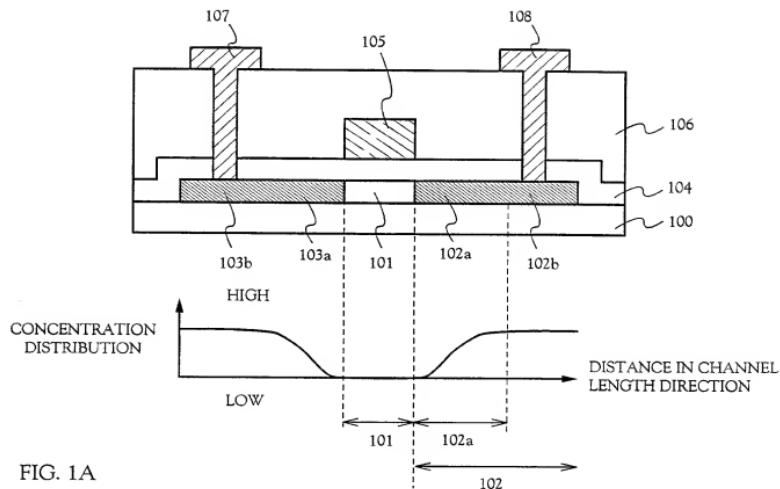


FIG. 1A

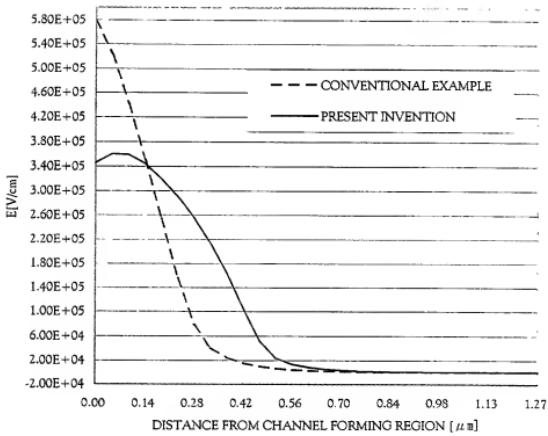


FIG. 1B

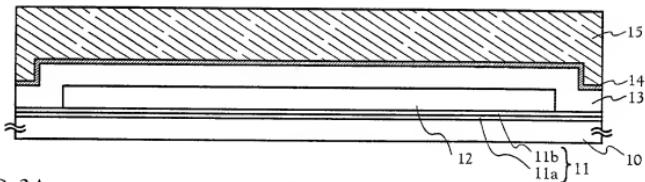


FIG. 2A

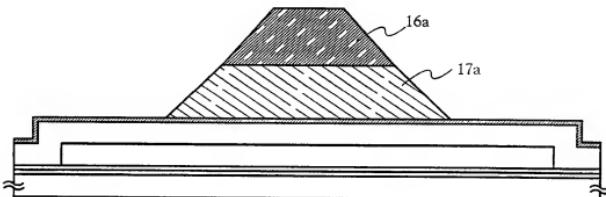


FIG. 2B

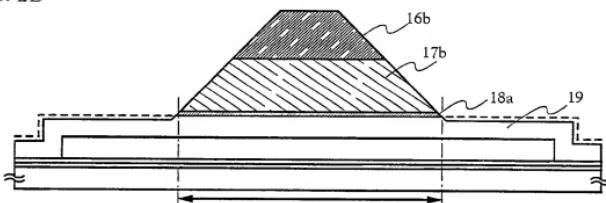


FIG. 2C

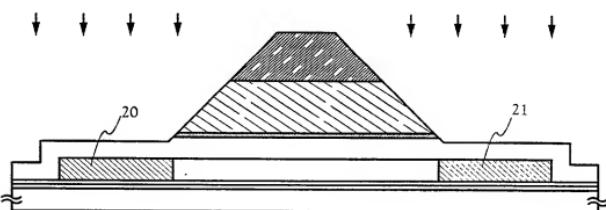


FIG. 2D

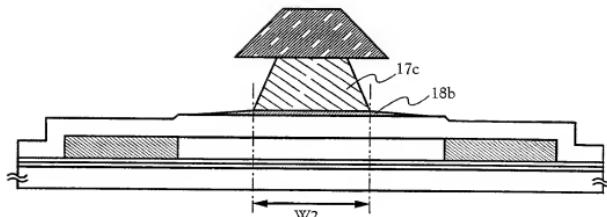


FIG. 3A

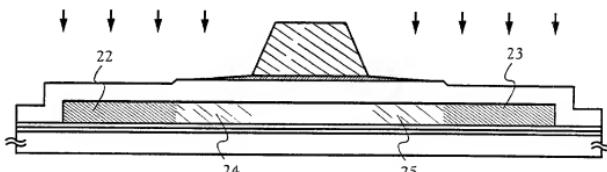


FIG. 3B

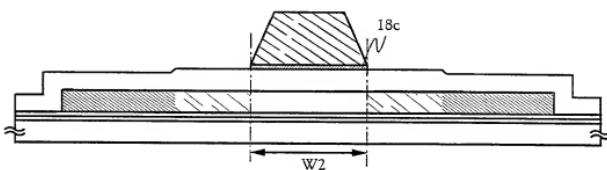


FIG. 3C

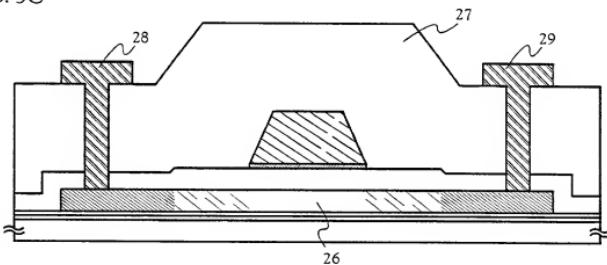


FIG. 3D

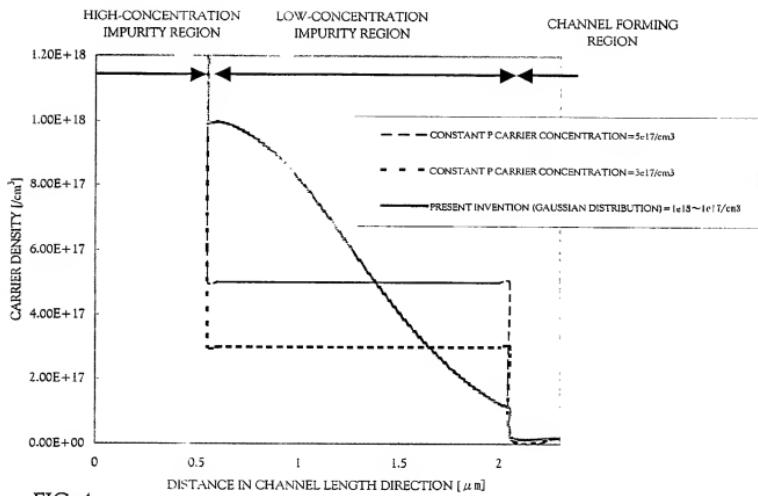


FIG. 4

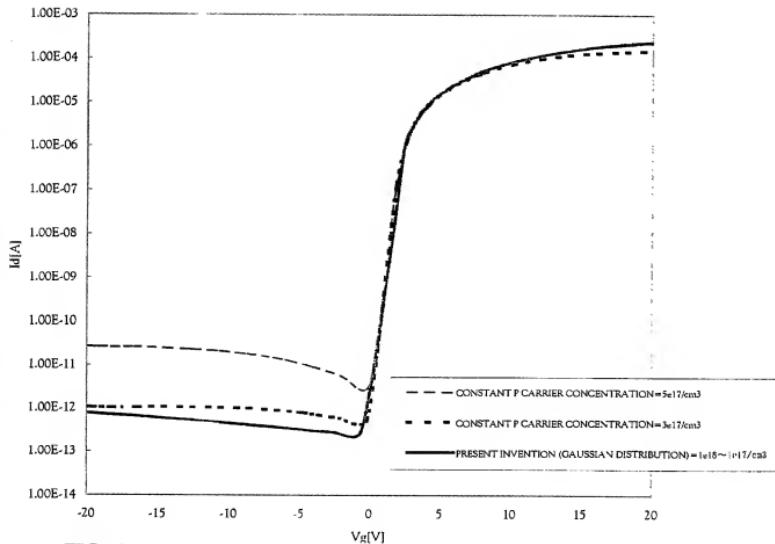


FIG. 5

I_d - V_g CURVE $V_d = 14V$ $L/W = 6/4$

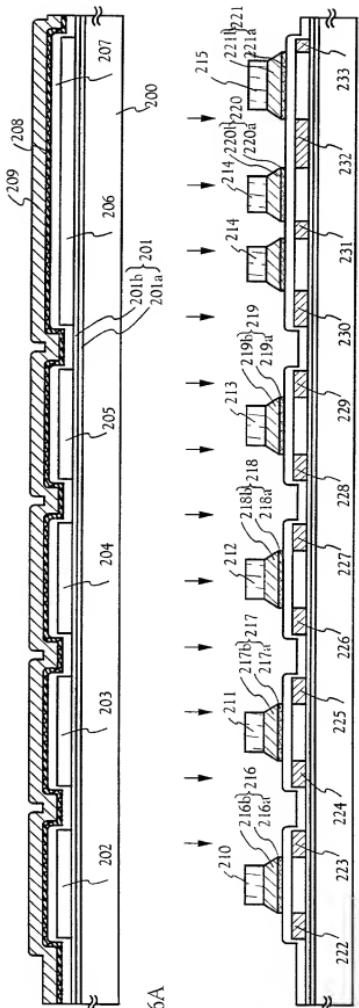


FIG. 6A

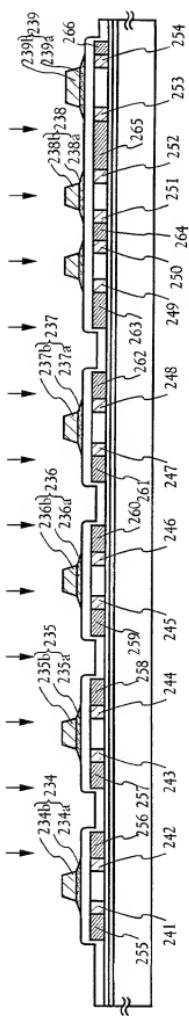


FIG. 6B

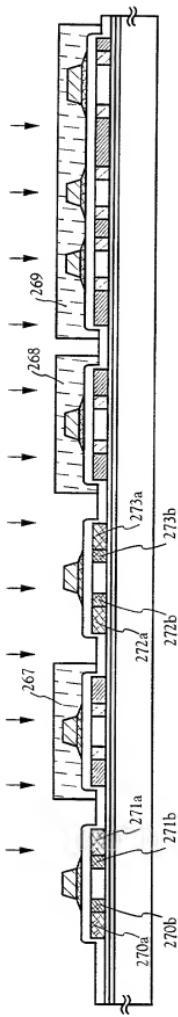


FIG. 7A

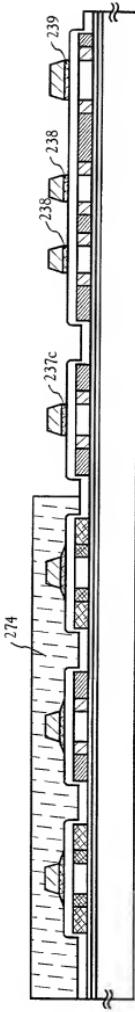


FIG. 7B

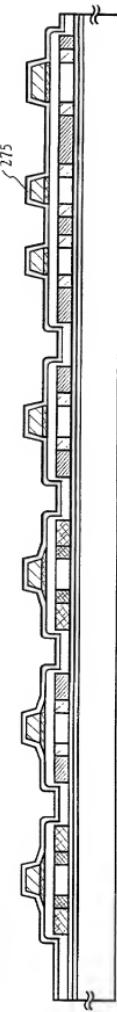


FIG. 7C

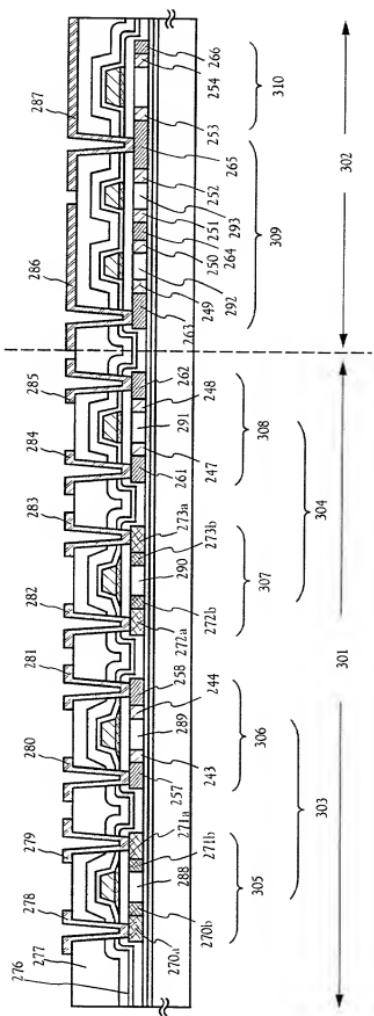


FIG. 8

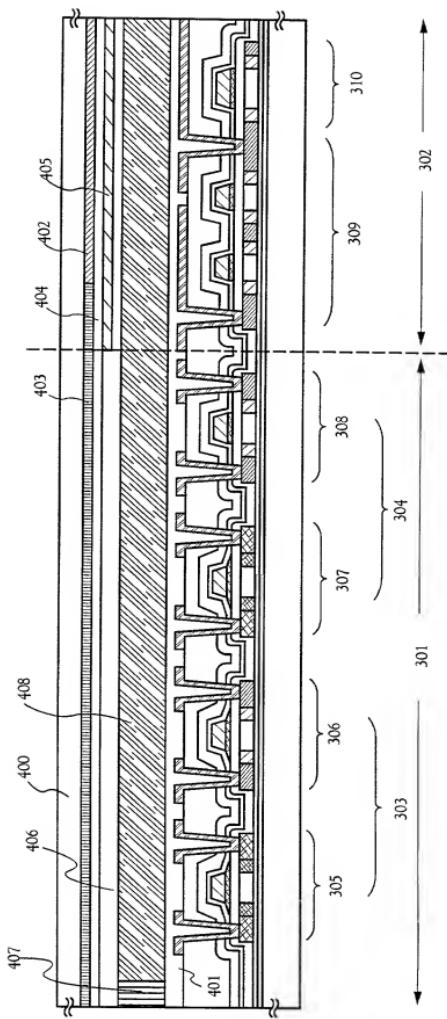


FIG. 9

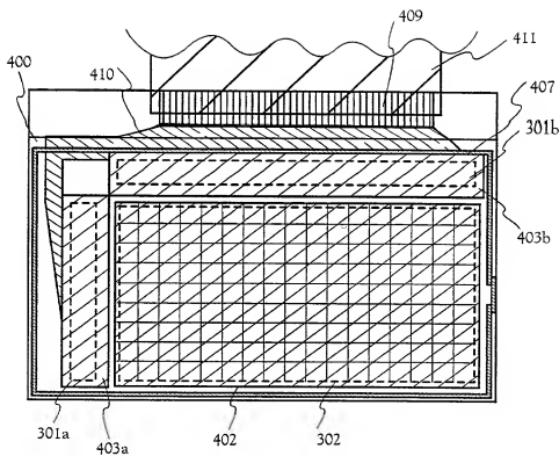
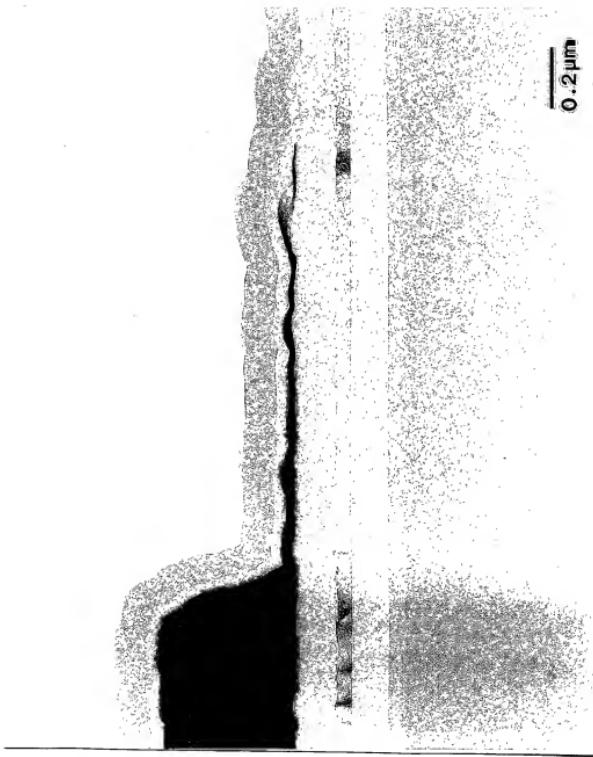


FIG. 10



TEM PHOTOGRAPH
(CROSS SECTION)

FIG. 11



TEM PHOTOGRAPH
(CROSS SECTION)

FIG. 12

(N-ch, L/W= 6/4, T_{ox} = 115)

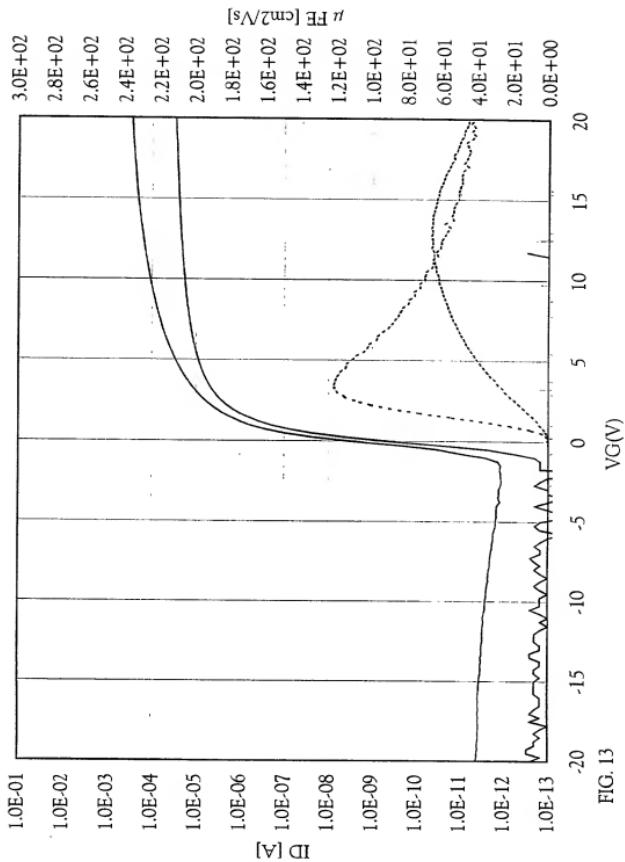


FIG. 13

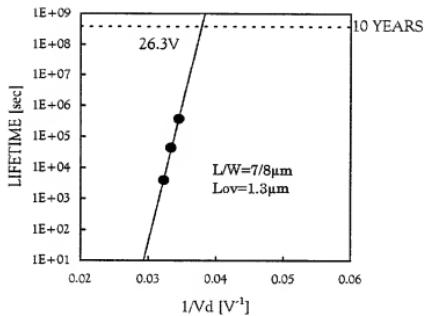
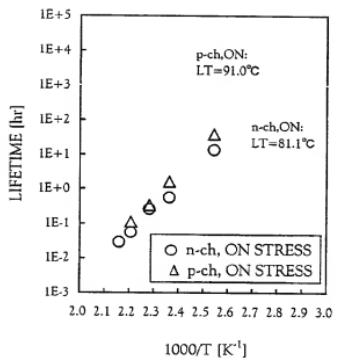
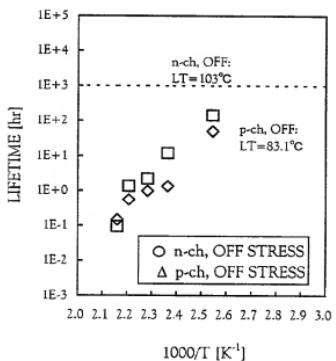


FIG. 14 DRIVING CIRCUIT TFT
10-YEAR GUARANTEE VOLTAGE



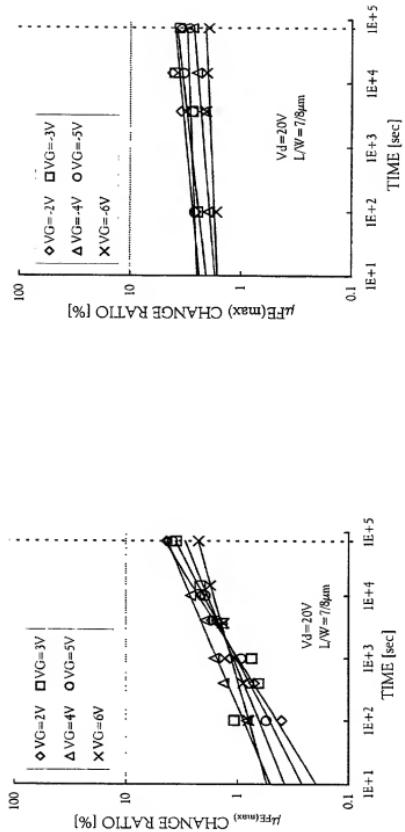
1000-HOUR LIFETIME TEMPERATURE
UNDER ON STRESS
(Δ shift_1=0.1V)

FIG. 15



1000-HOUR LIFETIME TEMPERATURE
UNDER OFF STRESS
(Δshift_1=0.1V)

FIG. 16



CHARACTERISTICS CHANGE OF
N-CHANNEL TFT
UNDER TRANSIENT STRESS

CHARACTERISTICS CHANGE OF
P-CHANNEL TFT
UNDER TRANSIENT STRESS

FIG. 17A

FIG. 17B

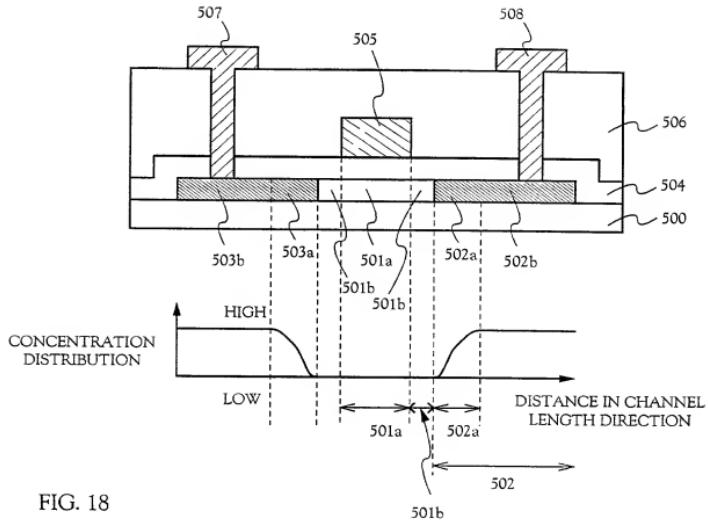


FIG. 18

(N-ch, L/V = 6/4, Tox = 115)

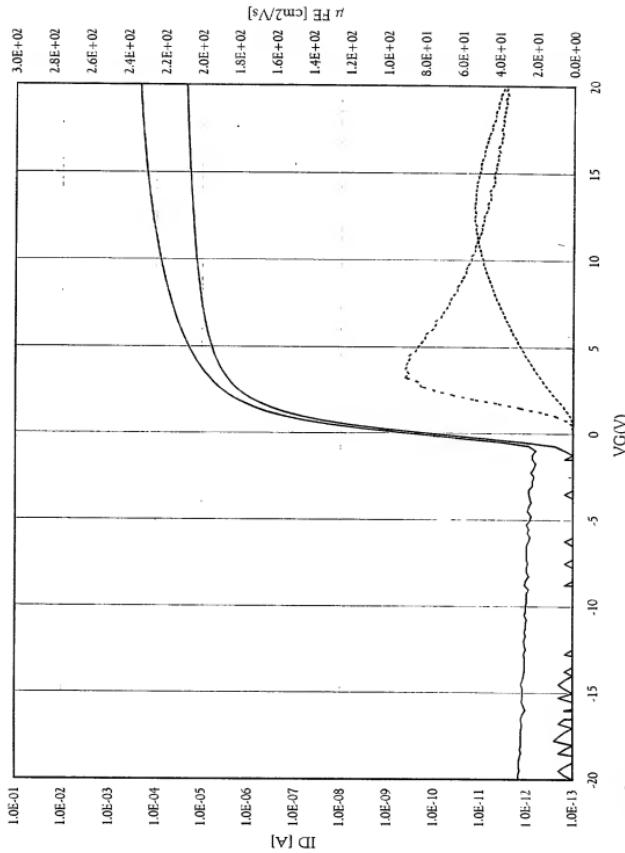


FIG. 19

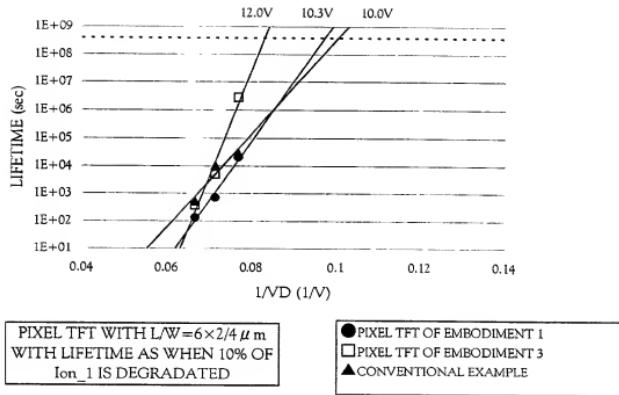


FIG. 20

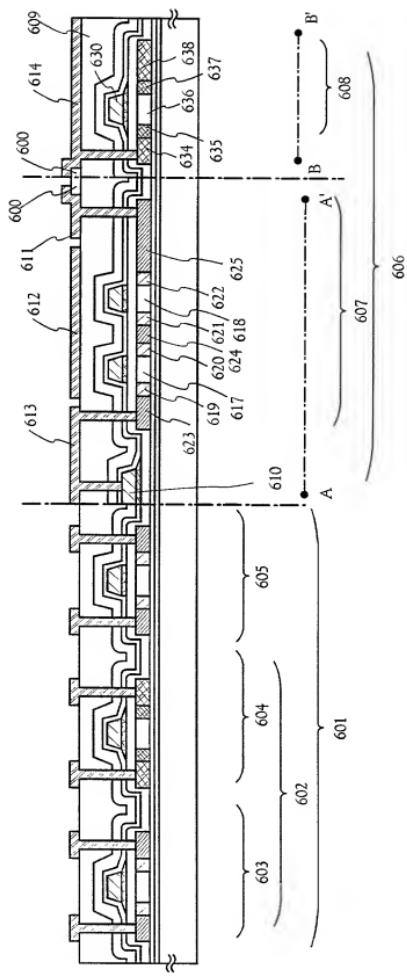


FIG. 21

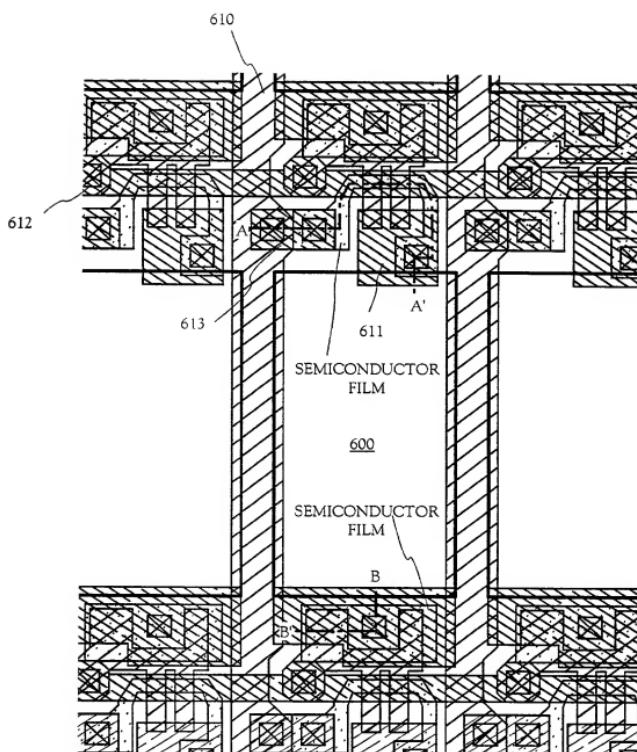


FIG. 22

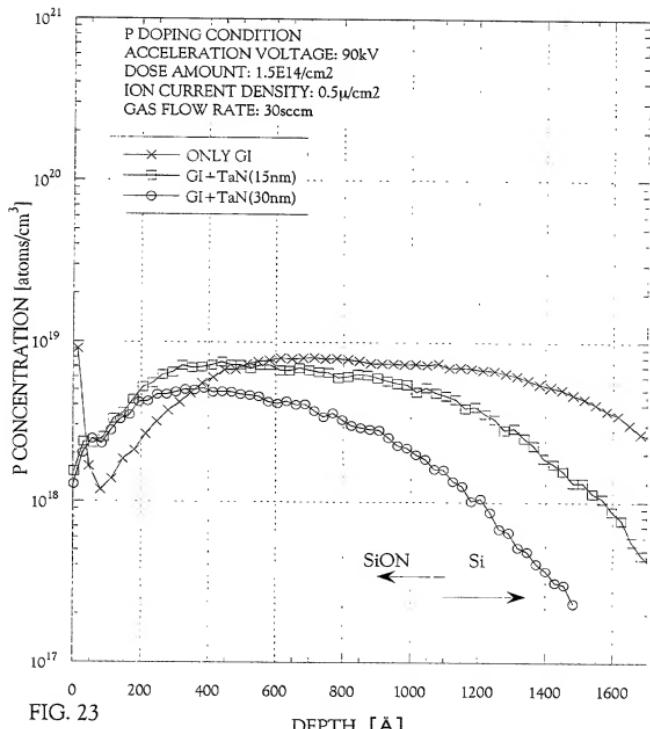


FIG. 23

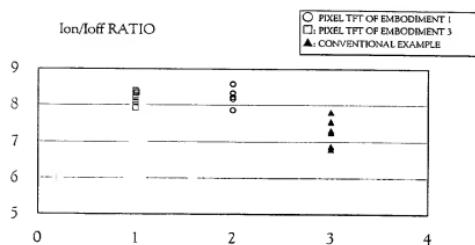
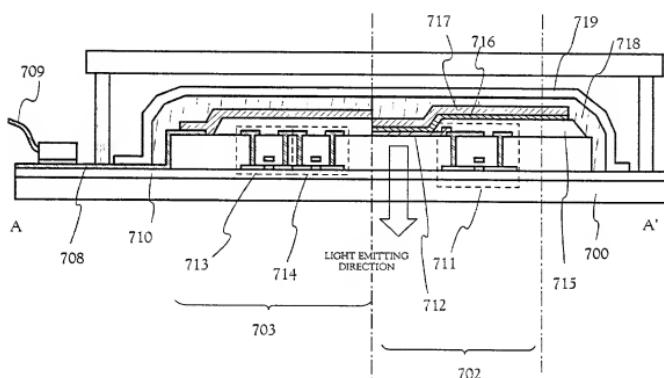
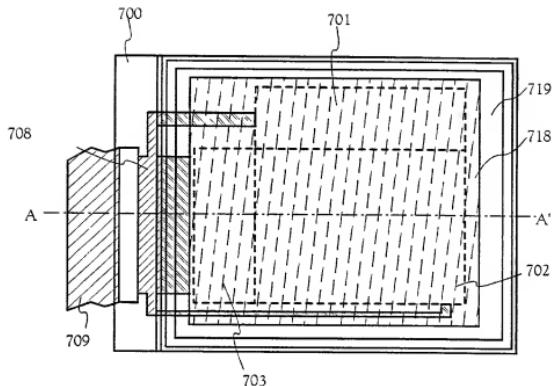


FIG. 24



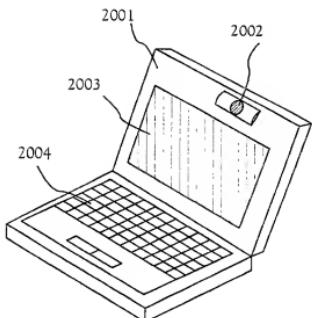


FIG. 26A

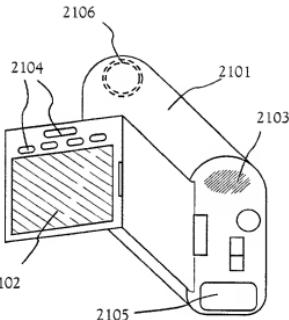


FIG. 26B

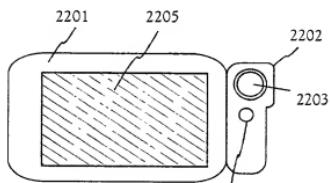


FIG. 26C

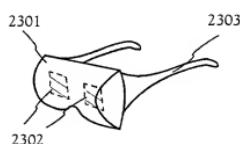


FIG. 26D

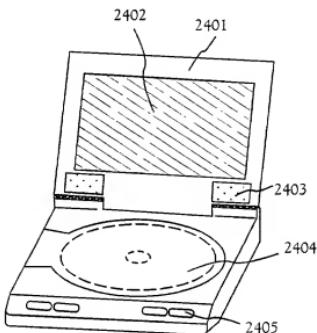


FIG. 26E

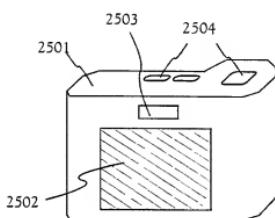


FIG. 26F

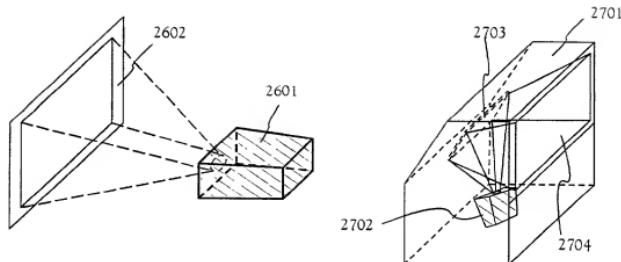


FIG. 27A

FIG. 27B

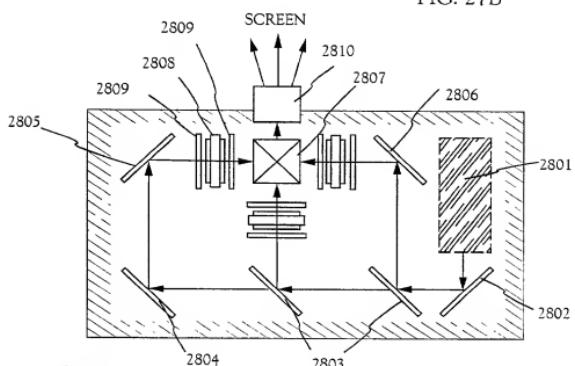


FIG. 27C

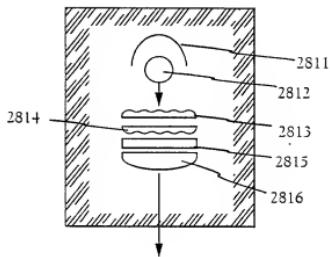


FIG. 27D

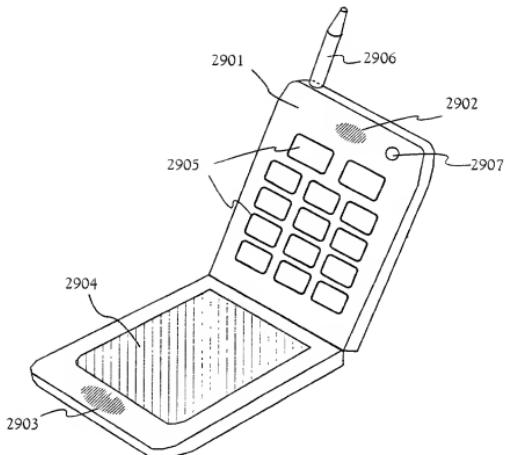


FIG. 28A

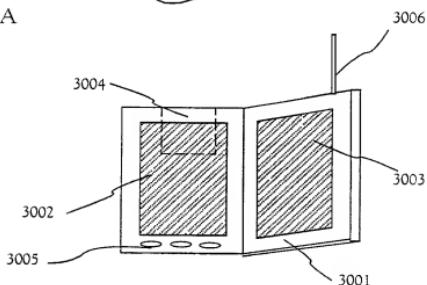


FIG. 28B

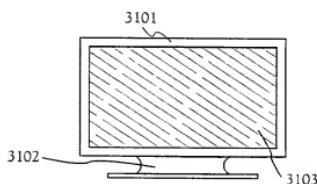


FIG. 28C

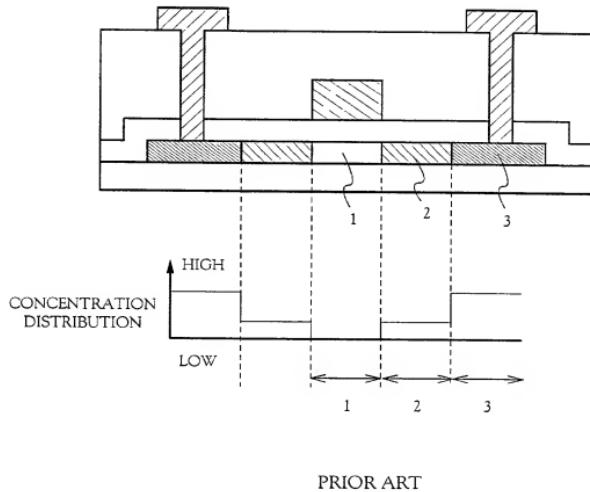


FIG. 29

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(N-ch, $L_{\text{NW}} = 6/4$, $T_{\text{ox}} = 115$)

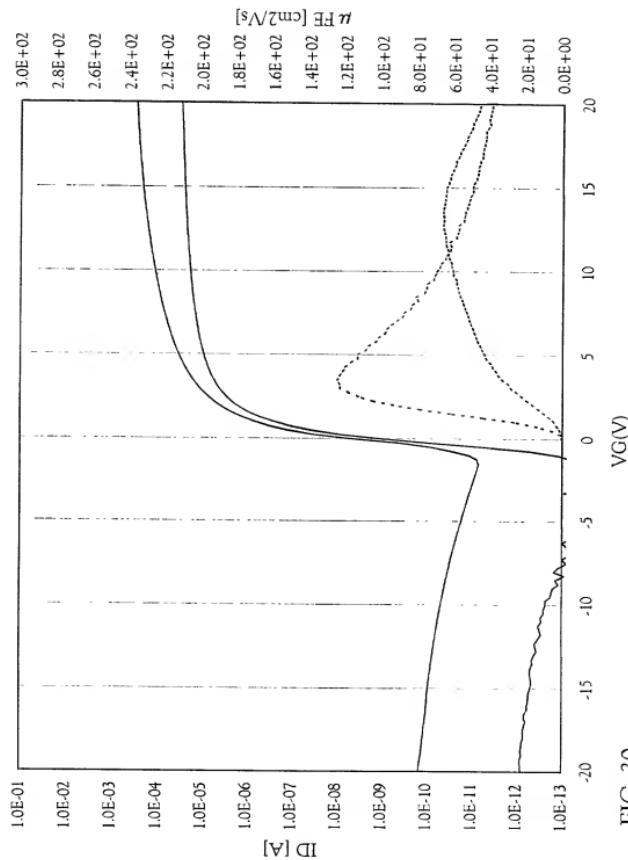
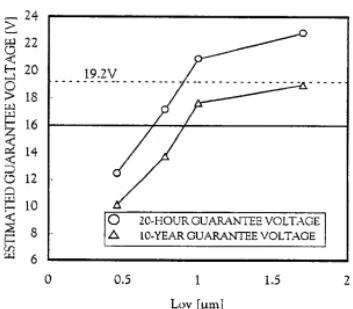
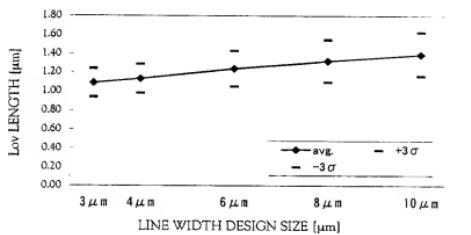


FIG. 30



DEPENDENCE ON LoV LENGTH OF ESTIMATED GUARANTEE VOLTAGE
(10% OF ON CURRENT IS DEGRADATED)
($L_g/W = 10/8 \mu m$)

FIG. 31



VARIATION OF LINE WIDTH DESIGN SIZE AND Low LENGTH

FIG. 32